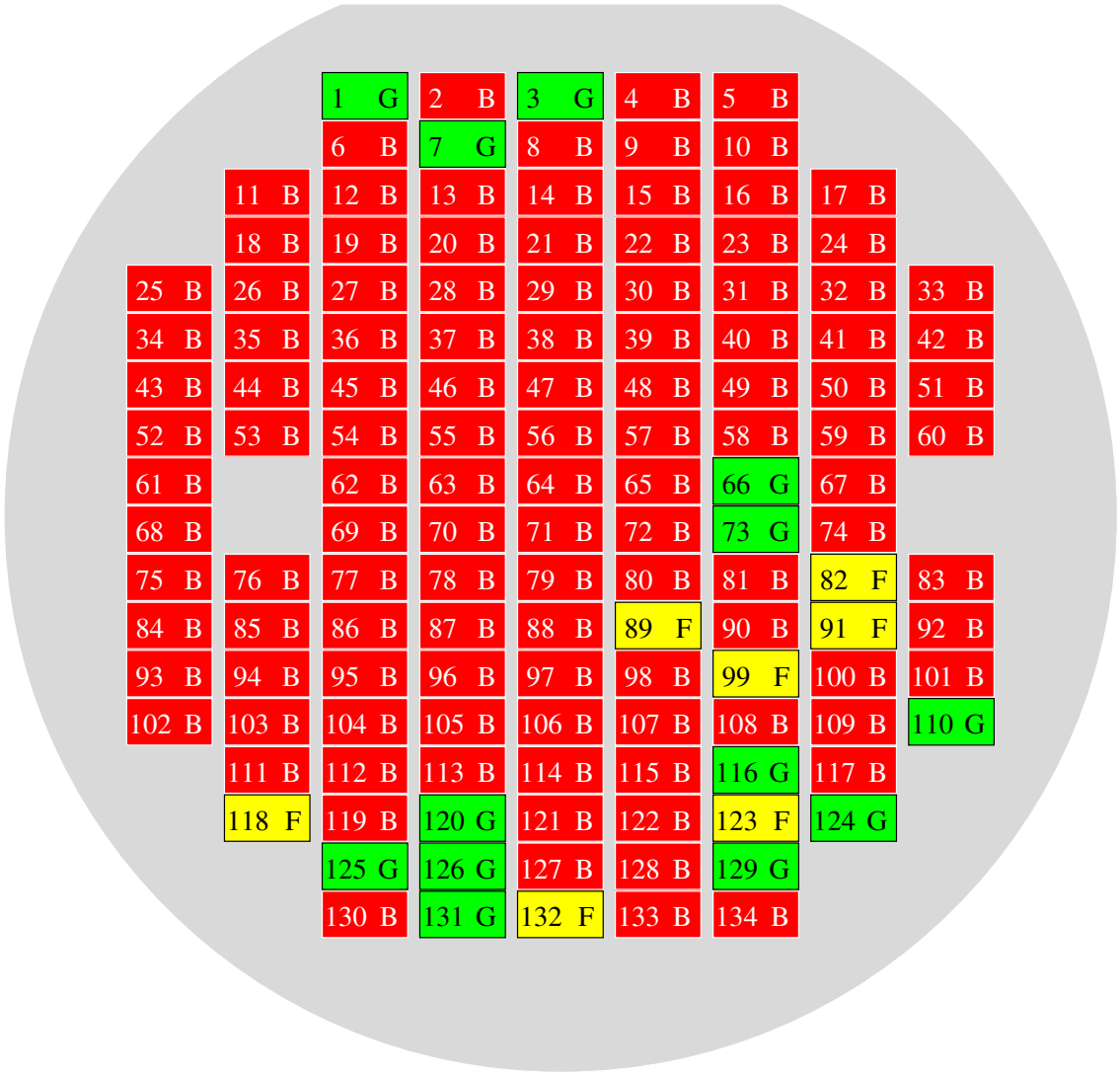
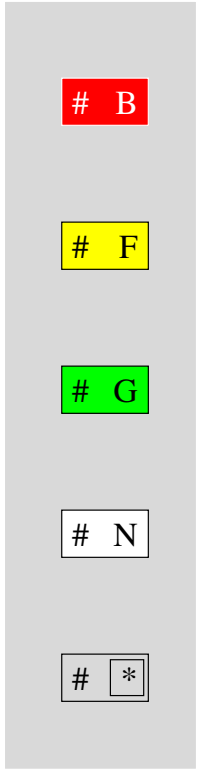
Die quality map for wafer 237 s/n: 21316-16-02

Date: 12/17/99





Bad die

Fair die

Good die

No info

Manually tagged